

## **AMENDMENTS TO THE SPECIFICATION:**

Please replace paragraph [0010] with the following rewritten paragraph:

- 1   **[0010]** In the preferred embodiment, the Built In Self Test method, for measuring  
2   jitter tolerance and jitter transfer on transceivers, makes use of transmit (TX) side  
3   interpolator to generate desired jitter test patterns. The TX serial data thus  
4   generated is looped back to the receive (RX) serial input. Pseudo Random  
5   Binary Sequence (PRBS) PRBS generation/verification mechanism is used to  
6   check jitter tolerance and a special up/down counter is used to monitor the  
7   movement of the RX clock recovery system and thus measure jitter transfer.

Please replace paragraph [0012] with the following rewritten paragraph:

- 1   **[0012]** Aspects of the present invention provide a Built-In Self-Test (BIST) BIST  
2   that can be performed on every device shipped and test for jitter tolerance and  
3   transfer. This test can be implemented simply by utilizing the PRBS checking  
4   mechanism that exists on present day devices. In some embodiments, an  
5   up/down counter is used to monitor activity of the receive clock recovery  
6   mechanism and test for jitter transfer.